## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q1/2022 to Q4/2023 Based on structural similarity

Supplier		User Part Number					
Nexperia B.V.		BAS16W-Q					
Name of Laboratory Assembly reliability labs Based on AEC-0101 Test		Part Description					
		Nexperia DHAM Small Signal Bipolar Diode					
		SMD package					
		Test Conditions	Duration	# Lots	# Quantity	# Rejects	
	TEST				<b>.</b> ,		
	Pre- and Post-Stress						
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
		JESD22-A113	,				
		Bake Tamb = 125 °C	24 hours				
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours				
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0	
	5	MIL-STD-750-1	•				
	HTRB	M1038 Method A					
		Tj = Tjmax, Vr = 100% of max. datasheet					
# B1	Bias	reverse voltage	1000 hours	110	4920	0	
	тс	JESD22-A104					
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	311	14080	0	
	. , ,					-	
	UHAST	JESD22-A118					
# A3 <b>or</b> # A3 alt	Unbiased HAST	Tamb = $130 ^{\circ}$ C, RH = $85 ^{\circ}$					
		JESD22-A102	—96 hours	311	14080	0	
	AC	Tamb = $121 ^{\circ}C$ , RH = $100 ^{\circ}M$					
	Autoclave	Pressure = $205 \text{ kPa} (29.7 \text{ psia})$					
	, , , , , , , , , , , , , , , , , , , ,						
	H3TRB	JESD22-A101					
	High Humidity High	Tamb = $85 ^{\circ}$ C, RH = $85\%$ , VR = $80\%$ of					
# A2 alt	Temperature Reverse Bias		1000 hours	311	14080	0	
# AZ dit			1000 110015	211	14000	U	
	IOL	MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta T_i =$					
# A5	IOL Intermittent Operating Life	, , , , , , , , , , , , , , , , , , , ,	1000 hours	312	14120	0	
# A3	Internitient Operating Life		1000 nours	312	14120	U	
	RSH	JESD22-A111					
# C8	Resistance to Solder Heat		10 -	260	0070	0	
# 10			10 s	269	8070	0	
# C10	SD Caldershility	1 CTD 003		222	6660	0	
# C10	Solderability	J-STD-002		222	6660	0	

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Small Signal Bipolar Diode	4920	0	0,86	1,16E+09

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